



Integrated Device Technology, Inc.

FAST CMOS 18-BIT REGISTERED TRANSCEIVER

IDT54/74FCT16500AT/CT/ET
IDT54/74FCT162500AT/CT/ET

FEATURES:

- **Common features:**
 - 0.5 MICRON CMOS Technology
 - **High-speed, low-power CMOS replacement for ABT functions**
 - **Typical tsk(o) (Output Skew) < 250ps**
 - **Low input and output leakage $\leq 1\mu\text{A}$ (max.)**
 - ESD > 2000V per MIL-STD-883, Method 3015; > 200V using machine model (C = 200pF, R = 0)
 - Packages include 25 mil pitch SSOP, 19.6 mil pitch TSSOP, 15.7 mil pitch TVSOP and 25 mil pitch Cerpack
 - Extended commercial range of -40°C to +85°C
 - VCC = 5V $\pm 10\%$
- **Features for FCT16500AT/CT/ET:**
 - High drive outputs (-32mA IOH, 64mA IOL)
 - Power off disable outputs permit "live insertion"
 - Typical VOLP (Output Ground Bounce) < 1.0V at VCC = 5V, TA = 25°C
- **Features for FCT162500AT/CT/ET:**
 - Balanced Output Drivers: $\pm 24\text{mA}$ (commercial), $\pm 16\text{mA}$ (military)
 - Reduced system switching noise
 - Typical VOLP (Output Ground Bounce) < 0.6V at VCC = 5V, TA = 25°C

bit registered transceivers are built using advanced dual metal CMOS technology. These high-speed, low-power 18-bit registered bus transceivers combine D-type latches and D-type flip-flops to allow data flow in transparent, latched and clocked modes. Data flow in each direction is controlled by output-enable (OEAB and OEBA), latch enable (LEAB and LEBA) and clock (CLKAB and CLKBA) inputs. For A-to-B data flow, the device operates in transparent mode when LEAB is HIGH. When LEAB is LOW, the A data is latched if CLKAB is held at a HIGH or LOW logic level. If LEAB is LOW, the A bus data is stored in the latch/flip-flop on the HIGH-to-LOW transition of CLKAB. OEAB performs the output enable function on the B port. Data flow from B port to A port is similar but uses OEBA, LEBA and CLKBA. Flow-through organization of signal pins simplifies layout. All inputs are designed with hysteresis for improved noise margin.

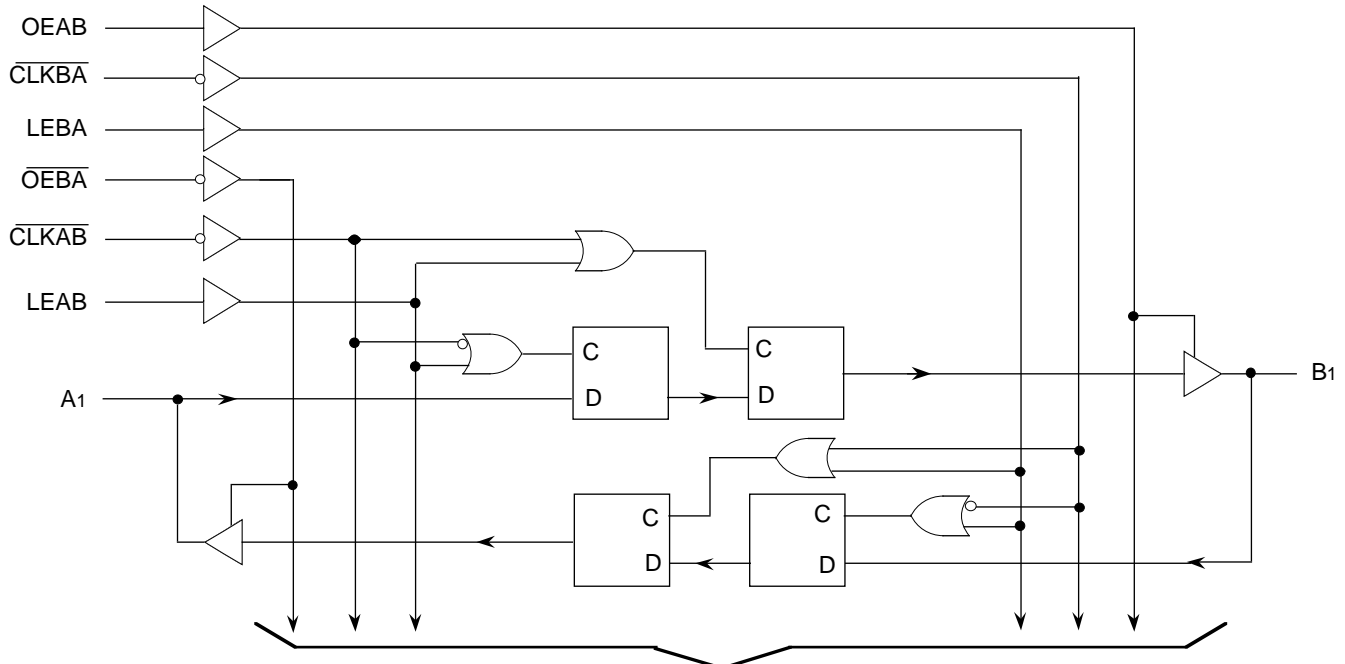
The FCT16500AT/CT/ET are ideally suited for driving high-capacitance loads and low-impedance backplanes. The output buffers are designed with power off disable capability to allow "live insertion" of boards when used as backplane drivers.

The FCT162500AT/CT/ET have balanced output drive with current limiting resistors. This offers low ground bounce, minimal undershoot, and controlled output fall times—reducing the need for external series terminating resistors. The FCT162500AT/CT/ET are plug-in replacements for the FCT16500AT/CT/ET and ABT16500 for on-board bus interface applications.

DESCRIPTION:

The FCT16500AT/CT/ET and FCT162500AT/CT/ET 18-

FUNCTIONAL BLOCK DIAGRAM



TO 17 OTHER CHANNELS

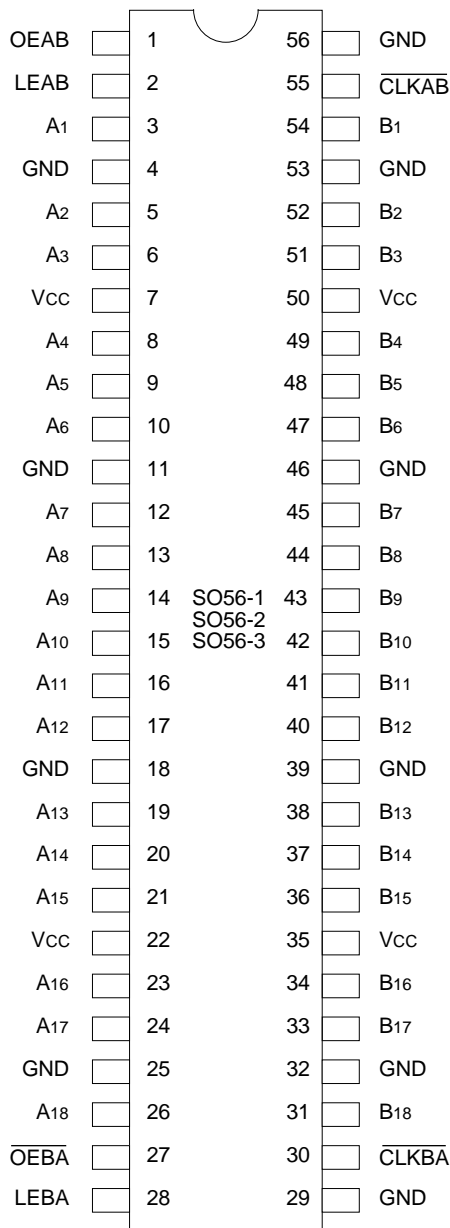
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MILITARY AND COMMERCIAL TEMPERATURE RANGES

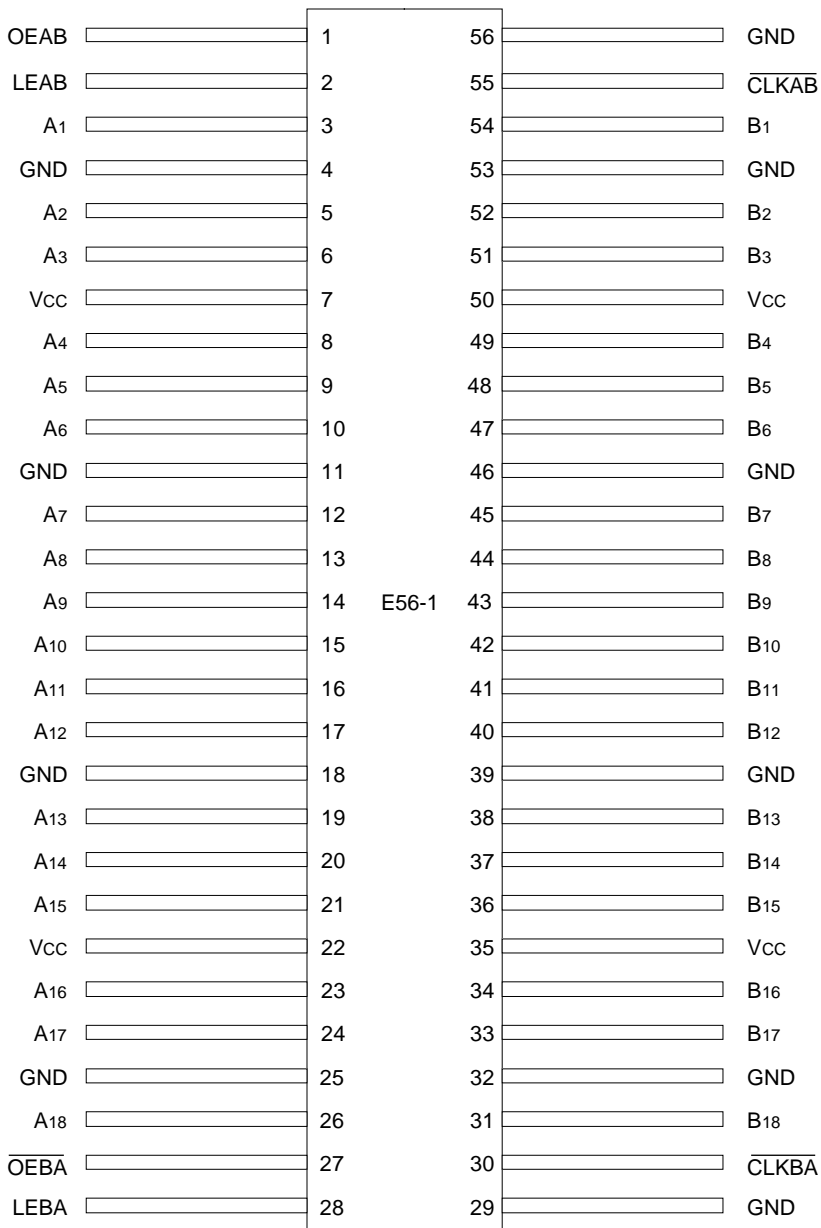
AUGUST 1996

PIN CONFIGURATIONS



**SSOP/
TSSOP/TVSOP
TOP VIEW**

2548 drw 02



**CERPACK
TOP VIEW**

2548 drw 03

PIN DESCRIPTION

Pin Names	Description
OEAB	A-to-B Output Enable Input
\overline{OEBA}	B-to-A Output Enable Input (Active LOW)
LEAB	A-to-B Latch Enable Input
LEBA	B-to-A Latch Enable Input
\overline{CLKAB}	A-to-B Clock Input (Active LOW)
\overline{CLKBA}	B-to-A Clock Input (Active LOW)
Ax	A-to-B Data Inputs or B-to-A 3-State Outputs
Bx	B-to-A Data Inputs or A-to-B 3-State Outputs

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FUNCTION TABLE^(1,4)

Inputs				Outputs	
OEAB	LEAB	\overline{CLKAB}	Ax	Bx	
L	X	X	X	Z	
H	H	X	L	L	
H	H	X	H	H	
H	L	↓	L	L	
H	L	↓	H	H	
H	L	H	X	B ⁽²⁾	
H	L	L	X	B ⁽³⁾	

NOTES:

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- A-to-B data flow is shown. B-to-A data flow is similar but uses \overline{OEBA} , LEBA, and CLKBA.
- Output level before the indicated steady-state input conditions were established.
- Output level before the indicated steady-state input conditions were established, provided that \overline{CLKAB} was LOW before LEAB went LOW.
- H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care
Z = High-impedance
↓ = HIGH-to-LOW Transition

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Description	Max.	Unit
V _{TERM} ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to +7.0	V
V _{TERM} ⁽³⁾	Terminal Voltage with Respect to GND	-0.5 to V _{CC} + 0.5	V
T _{STG}	Storage Temperature	-65 to +150	°C
I _{OUT}	DC Output Current	-60 to +120	mA

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NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- All device terminals except FCT162XXXXT Output and I/O terminals.
- Output and I/O terminals for FCT162XXXXT.

CAPACITANCE (T_A = +25°C, f = 1.0MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Typ.	Max.	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V	3.5	6.0	pF
C _{I/O}	I/O Capacitance	V _{OUT} = 0V	3.5	8.0	pF

NOTE:

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- This parameter is measured at characterization but not tested.

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Commercial: $T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$, $V_{CC} = 5.0\text{V} \pm 10\%$; Military: $T_A = -55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$, $V_{CC} = 5.0\text{V} \pm 10\%$

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
V_{IH}	Input HIGH Level	Guaranteed Logic HIGH Level		2.0	—	—	V
V_{IL}	Input LOW Level	Guaranteed Logic LOW Level		—	—	0.8	V
I_{IH}	Input HIGH Current (Input pins) ⁽⁵⁾	$V_{CC} = \text{Max.}$	$V_I = V_{CC}$	—	—	± 1	μA
	Input HIGH Current (I/O pins) ⁽⁵⁾			—	—	± 1	
I_{IL}	Input LOW Current (Input pins) ⁽⁵⁾		$V_I = \text{GND}$	—	—	± 1	
	Input LOW Current (I/O pins) ⁽⁵⁾			—	—	± 1	
I_{OZH}	High Impedance Output Current (3-State Output pins) ⁽⁵⁾	$V_{CC} = \text{Max.}$	$V_O = 2.7\text{V}$	—	—	± 1	μA
I_{OZL}			$V_O = 0.5\text{V}$	—	—	± 1	
V_{IK}	Clamp Diode Voltage	$V_{CC} = \text{Min.}, I_{IN} = -18\text{mA}$		—	-0.7	-1.2	V
I_{OS}	Short Circuit Current	$V_{CC} = \text{Max.}, V_O = \text{GND}^{(3)}$		-80	-140	-225	mA
V_H	Input Hysteresis	—		—	100	—	mV
I_{CCL} I_{CCH} I_{CCZ}	Quiescent Power Supply Current	$V_{CC} = \text{Max.}, V_{IN} = \text{GND}$ or V_{CC}		—	5	500	μA

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OUTPUT DRIVE CHARACTERISTICS FOR FCT16500T

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
I_O	Output Drive Current	$V_{CC} = \text{Max.}, V_O = 2.5\text{V}^{(3)}$		-50	—	-180	mA
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{Min.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -3\text{mA}$	2.5	3.5	—	V
			$I_{OH} = -12\text{mA MIL.}$ $I_{OH} = -15\text{mA COM'L.}$	2.4	3.5	—	V
			$I_{OH} = -24\text{mA MIL.}$ $I_{OH} = -32\text{mA COM'L.}^{(4)}$	2.0	3.0	—	V
V_{OL}	Output LOW Voltage	$V_{CC} = \text{Min.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 48\text{mA MIL.}$ $I_{OL} = 64\text{mA COM'L.}$	—	0.2	0.55	V
I_{OFF}	Input/Output Power Off Leakage ⁽⁵⁾	$V_{CC} = 0\text{V}, V_{IN}$ or $V_O \leq 4.5\text{V}$		—	—	± 1	μA

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OUTPUT DRIVE CHARACTERISTICS FOR FCT162500T

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
I_{ODL}	Output LOW Current	$V_{CC} = 5\text{V}, V_{IN} = V_{IH}$ or $V_{IL}, V_{OUT} = 1.5\text{V}^{(3)}$		60	115	200	mA
I_{ODH}	Output HIGH Current	$V_{CC} = 5\text{V}, V_{IN} = V_{IH}$ or $V_{IL}, V_{OUT} = 1.5\text{V}^{(3)}$		-60	-115	-200	mA
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{Min.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -16\text{mA MIL.}$ $I_{OH} = -24\text{mA COM'L.}$	2.4	3.3	—	V
V_{OL}	Output LOW Voltage	$V_{CC} = \text{Min.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 16\text{mA MIL.}$ $I_{OL} = 24\text{mA COM'L.}$	—	0.3	0.55	V

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NOTES:

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 5.0\text{V}, +25^{\circ}\text{C}$ ambient.
- Not more than one output should be tested at one time. Duration of the test should not exceed one second.
- Duration of the condition can not exceed one second.
- The test limit for this parameter is $\pm 5\mu\text{A}$ at $T_A = -55^{\circ}\text{C}$.

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
ΔI_{CC}	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V^{(3)}$		—	0.5	1.5	mA
I_{CCD}	Dynamic Power Supply Current ⁽⁴⁾	$V_{CC} = \text{Max.}, \text{Outputs Open}$ $OEAB = \overline{OEBA} = V_{CC} \text{ or GND}$ One Input Toggling 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	75	120	$\mu A/$ MHz
I_C	Total Power Supply Current ⁽⁶⁾	$V_{CC} = \text{Max.}, \text{Outputs Open}$ $f_{CP} = 10\text{MHz (CLKAB)}$ 50% Duty Cycle $OEAB = \overline{OEBA} = V_{CC}$ $LEAB = \text{GND}$ One Bit Toggling $f_i = 5\text{MHz}$ 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	0.8	1.7	mA
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	1.3	3.2	
		$V_{CC} = \text{Max.}, \text{Outputs Open}$ $f_{CP} = 10\text{MHz (CLKAB)}$ 50% Duty Cycle $OEAB = \overline{OEBA} = V_{CC}$ $LEAB = \text{GND}$ Eighteen Bits Toggling $f_i = 2.5\text{MHz}$ 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	3.8	6.5 ⁽⁵⁾	
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	8.5	20.8 ⁽⁵⁾	

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NOTES:

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 5.0V$, $+25^\circ C$ ambient.
- Per TTL driven input ($V_{IN} = 3.4V$). All other inputs at V_{CC} or GND .
- This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
- $I_C = I_{\text{QUIESCENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$
 $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_{CP} N_{CP} / 2 + f_i N_i)$
 $I_{CC} = \text{Quiescent Current (} I_{CCL}, I_{CCH} \text{ and } I_{CCZ})$
 $\Delta I_{CC} = \text{Power Supply Current for a TTL High Input (} V_{IN} = 3.4V)$
 $D_H = \text{Duty Cycle for TTL Inputs High}$
 $N_T = \text{Number of TTL Inputs at } D_H$
 $I_{CCD} = \text{Dynamic Current Caused by an Input Transition Pair (HLH or LHL)}$
 $f_{CP} = \text{Clock Frequency for Register Devices (Zero for Non-Register Devices)}$
 $N_{CP} = \text{Number of Clock Inputs at } f_{CP}$
 $f_i = \text{Input Frequency}$
 $N_i = \text{Number of Inputs at } f_i$

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

Symbol	Parameter	Condition ⁽¹⁾	FCT16500AT/162500AT				FCT16500CT/162500CT				FCT16500ET/162500ET				Unit
			Com'l.		Mil.		Com'l.		Mil.		Com'l.		Mil.		
			Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	
f _{MAX}	CLKAB or CLKBA frequency ⁽⁴⁾	CL = 50pF	—	150	—	150	—	150	—	150	—	150	—	—	MHz
t _{PLH} t _{PHL}	Propagation Delay Ax to Bx or Bx to Ax	RL = 500Ω	1.5	5.1	1.5	5.6	1.5	4.6	1.5	4.6	—	3.8	—	—	ns
t _{PLH} t _{PHL}	Propagation Delay LEBA to Ax, LEAB to Bx		1.5	5.6	1.5	6.0	1.5	5.3	1.5	5.6	—	4.2	—	—	ns
t _{PLH} t _{PHL}	Propagation Delay CLKBA to Ax, CLKAB to Bx		1.5	5.6	1.5	6.0	1.5	5.3	1.5	5.4	—	4.2	—	—	ns
t _{PZH} t _{PZL}	Output Enable Time OEBA to Ax, OEAB to Bx		1.5	6.0	1.5	6.4	1.5	5.6	1.5	6.0	—	4.8	—	—	ns
t _{PHZ} t _{PLZ}	Output Disable Time OEBA to Ax, OEAB to Bx		1.5	5.6	1.5	6.0	1.5	5.2	1.5	5.6	—	4.0	—	—	ns
t _{SU}	Set-up Time, HIGH or LOW Ax to CLKAB, Bx to CLKBA		3.0	—	3.0	—	3.0	—	3.0	—	2.4	—	—	—	ns
t _H	Hold Time, HIGH or LOW Ax to CLKAB, Bx to CLKBA		0	—	0	—	0	—	0	—	0	—	—	—	ns
t _{SU}	Set-up Time HIGH or LOW Ax to LEAB, Bx to LEBA	Clock HIGH	3.0	—	3.0	—	3.0	—	3.0	—	2.0	—	—	—	ns
		Clock LOW	1.5	—	1.5	—	1.5	—	1.5	—	1.5	—	—	—	ns
t _H	Hold Time, HIGH or LOW Ax to LEAB, Bx to LEBA		1.5	—	1.5	—	1.5	—	1.5	—	0.5	—	—	—	ns
t _W	LEAB or LEBA Pulse Width HIGH ⁽⁴⁾		3.0	—	3.0	—	3.0	—	3.0	—	3.0	—	—	—	ns
t _W	CLKAB or CLKBA Pulse Width HIGH or LOW ⁽⁴⁾		3.0	—	3.0	—	3.0	—	3.0	—	3.0	—	—	—	ns
t _{SK(o)}	Output Skew ⁽³⁾		—	0.5	—	0.5	—	0.5	—	0.5	—	0.5	—	—	ns

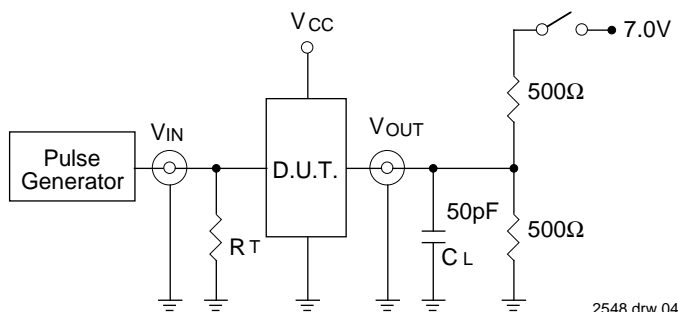
NOTES:

1. See test circuits and waveforms.
2. Minimum limits are guaranteed but not tested on Propagation Delays.
3. Skew between any two outputs of the same package switching in the same direction. This parameter is guaranteed by design.
4. This parameter is guaranteed but not tested.

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TEST CIRCUITS AND WAVEFORMS

TEST CIRCUITS FOR ALL OUTPUTS



SWITCH POSITION

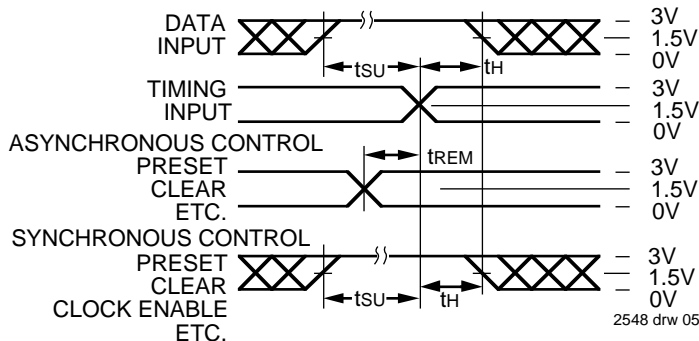
Test	Switch
Open Drain Disable Low Enable Low	Closed
All Other Tests	Open

DEFINITIONS:

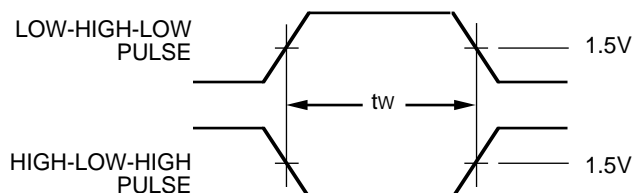
CL = Load capacitance: includes jig and probe capacitance.
RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.

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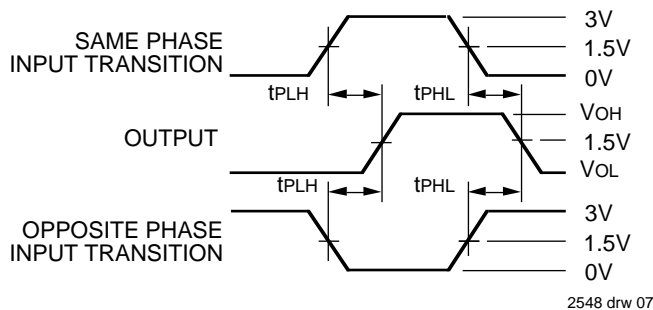
SET-UP, HOLD AND RELEASE TIMES



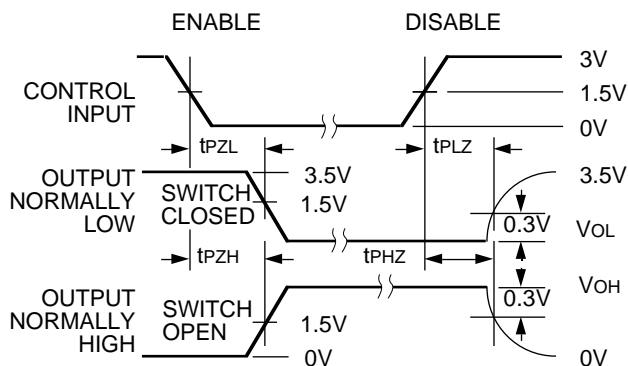
PULSE WIDTH



PROPAGATION DELAY



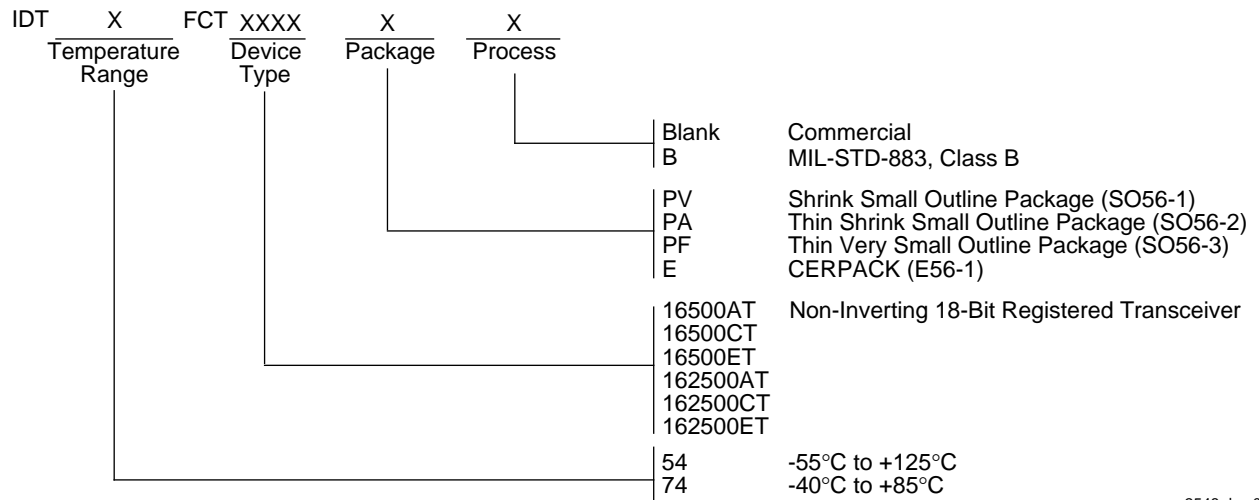
ENABLE AND DISABLE TIMES



NOTES:

- Diagram shown for input Control Enable-LOW and input Control Disable-HIGH
- Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $t_f \leq 2.5\text{ns}$; $t_r \leq 2.5\text{ns}$

ORDERING INFORMATION



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